Signetics

FAST 74F395
Shift Register

FAST Products

4-Bit Cascadable Shift Register (3-state)

Product Specification

FEATURES
- **4-bit parallel load shift register**
- **Independent 3-state buffer outputs, Q_0-Q_3**
- **Separate Q_s output for serial expansion**
- **Asynchronous Master Reset**

TYPE	TYPICAL f_{MAX}	TYPICAL SUPPLY CURRENT (TOTAL)
74F395	120MHz	32mA

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE V_{CC} = 5V±10%; T_A = 0°C to +70°C
16-Pin Plastic DIP	N74F395N
16-Pin Plastic SO	N74F395D

DESCRIPTION
The 74F395 is a 4-bit Shift Register with serial and parallel synchronous operating modes and 3-state buffer outputs.The shifting and loading operations are controlled by the state of the Parallel Enable (PE) input. When PE is High, data is loaded from the Parallel Data inputs (D_0 - D_3) into the register synchronous with the High-to-Low transition of the Clock input (CP). When PE is Low, the data at the Serial Data input (D_s) is loaded into the Q_0 flip-flop, and the data in the register is shifted one bit to the right in the direction ($Q_0 \rightarrow Q_1 \rightarrow Q_2 \rightarrow Q_3$) synchronous with the negative clock transition. The PE and Data inputs are fully edge-triggered and must be stable one setup prior to the High-to-Low transition of the clock.

The Master Reset ($\overline{MR}$) is an asynchronous active-Low input. When Low, the $\overline{MR}$ overrides the clock and all other inputs and clears the register.

The 3-state output buffers are designed to drive heavily loaded 3-state buses, or large capacitive loads.

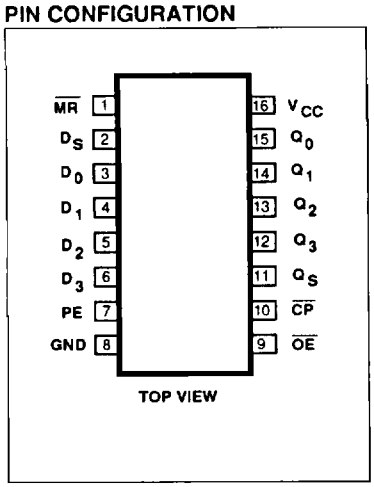
The active-Low Output Enable ($\overline{OE}$) controls all four 3-state buffers independent of the register operation. The data in the register appears at the outputs when $\overline{OE}$ is Low. The outputs are in High impedance "OFF" state, which means they will neither drive nor load the bus when $\overline{OE}$ is High. The output from the last stage is brought out separately. This output (Q_s) is tied to the Serial Data input (D_s) of the next register for serial expansion applications.The Q_s output is not affected by the 3-state buffer operation.

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

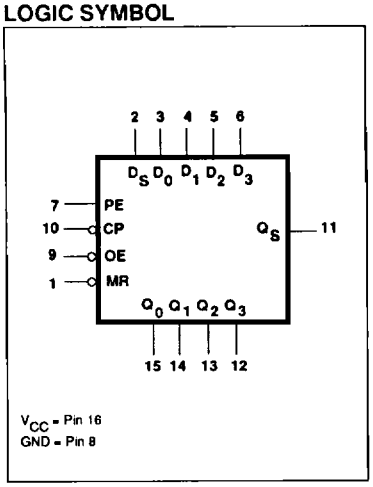
PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D_0 - D_3	Data inputs	1.0/1.0	20µA/0.6mA
D_s	Serial data input	1.0/1.0	20µA/0.6mA
PE	Parallel Enable input	1.0/1.0	20µA/0.6mA
$\overline{MR}$	Master Reset input (active Low)	1.0/1.0	20µA/0.6mA
$\overline{OE}$	Output Enable input (active Low)	1.0/1.0	20µA/0.6mA
$\overline{CP}$	Clock Pulse input (active falling edge)	1.0/1.0	20µA/0.6mA
Q_s	Serial expansion output	50/33	1.0mA/20mA
Q_0 - Q_3	Data outputs (3-state)	150/40	3.0mA/24mA

NOTE:
One (1.0) FAST Unit Load is defined as: 20µA in the High state and 0.6mA in the Low state.

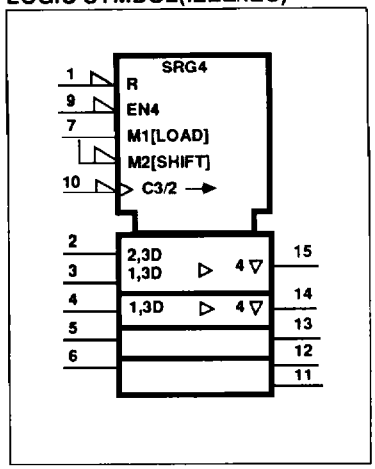
PIN CONFIGURATION



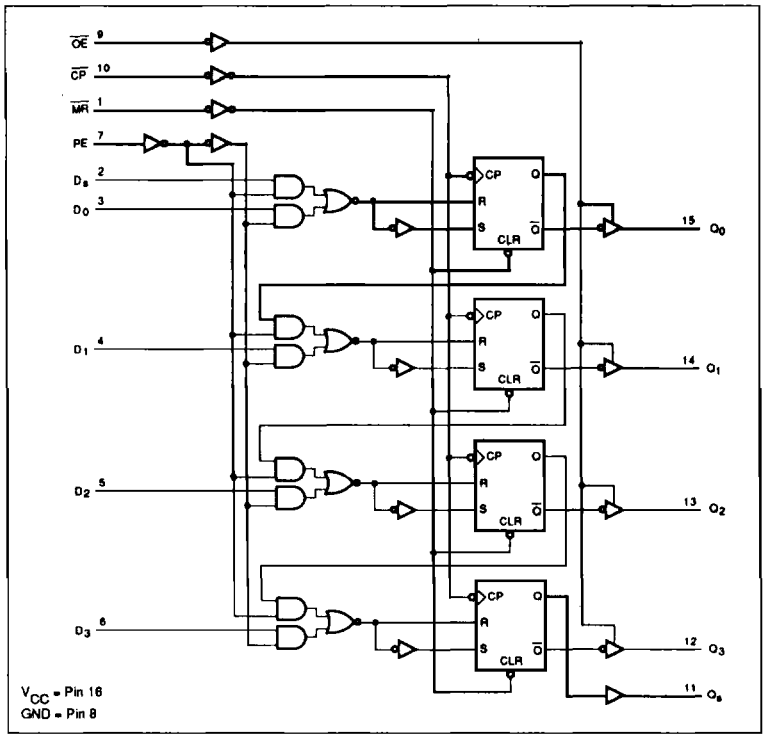
LOGIC SYMBOL



LOGIC SYMBOL(IEEE/IEC)



LOGIC DIAGRAM



MODE SELECT-FUNCTION TABLE

INPUTS					OUTPUTS				REGISTER OPERATING MODES
$\overline{MR}$	$\overline{CP}$	PE	D_S	D_n	Q_0	Q_1	Q_2	Q_3	
L	X	X	X	X	L	L	L	L	Reset (clear)
H	↓	l	l	X	L	q_0	q_1	q_2	Shift right
H	↓	l	h	X	H	q_0	q_1	q_2	
H	↓	h	X	l	L	L	L	L	Parallel load
H	↓	h	X	h	H	H	H	H	

INPUTS		OUTPUTS		3-STATE BUFFER OPERATING MODES
$\overline{OE}$	Q_n (Register)	Q_0, Q_1, Q_2, Q_3	Q_S	
L	L	L	L	Read
L	H	H	H	
H	L	Z	L	Disable buffers
H	H	Z	H	

H = High voltage level
h = High voltage level one set-up time prior to the High-to-Low clock transition
L = Low voltage level
l = Low voltage level one set-up time prior to the High-to-Low clock transition
q_n = Lower case letters indicate the state of the referenced input (or output) one set-up time prior to the High-to-Low clock transition
X = Don't care
Z = High impedance "OFF" state
↓ = High-to-Low clock transition

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V_{CC}	Supply voltage		-0.5 to +7.0	V
V_{IN}	Input voltage		-0.5 to +7.0	V
I_{IN}	Input current		-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state		-0.5 to +5.5	V
I_{OUT}	Current applied to output in Low output state	Q_S	40	mA
		Q_0-Q_3	48	mA
T_A	Operating free-air temperature range		0 to +70	°C
T_{STG}	Storage temperature		-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER		LIMITS			UNIT
			Min	Nom	Max	
V_{CC}	Supply voltage		4.5	5.0	5.5	V
V_{IH}	High-level input voltage		2.0			V
V_{IL}	Low-level input voltage				0.8	V
I_{IK}	Input clamp current				-18	mA
I_{OH}	High-level output current	Q_S			-1	mA
		Q_0-Q_3			-3	mA
I_{OL}	Low-level output current	Q_S			20	mA
		Q_0-Q_3			24	mA
T_A	Operating free-air temperature range		0		70	°C

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIONS[1]			LIMITS Min	LIMITS Typ[2]	LIMITS Max	UNIT
V_{OH}	High-level output voltage	Q_S	V_{CC} = MIN, V_{IL} = MAX V_{IH} = MIN,	I_{OH}=-1mA	±10%V_{CC}	2.5			V
					±5%V_{CC}	2.7	3.4		V
		Q_0- Q_3		I_{OH}=-3mA	±10%V_{CC}	2.4			V
					±5%V_{CC}	2.7			V
V_{OL}	Low-level output voltage		V_{CC} = MIN, V_{IL} = MAX V_{IH} = MIN,	I_{OL}=MAX	±10%V_{CC}		0.35	0.50	V
					±5%V_{CC}		0.35	0.50	V
V_{IK}	Input clamp voltage		V_{CC} = MIN, I_I = I_{IK}				-0.73	-1.2	V
I_I	Input current at maximum input voltage		V_{CC} = MAX, V_I = 7.0V					100	µA
I_{IH}	High-level input current		V_{CC} = MAX, V_I = 2.7V					20	µA
I_{IL}	Low-level input current		V_{CC} = MAX, V_I = 0.5V					-0.6	mA
I_{OZH}	Off-state output current High level voltage applied	Q_0- Q_3 only	V_{CC} = MAX, V_O= 2.7V					50	µA
I_{OZL}	Off-state output current Low level voltage applied	Q_0- Q_3 only	V_{CC} = MAX, V_O= 0.5V					-50	µA
I_{OS}	Short-circuitoutput current[3]		V_{CC} = MAX			-60		-150	mA
I_{CC}	Supply current (total)	I_{CCH}	V_{CC} = MAX	$\overline{MR}$=PE=D_n=D_s=4.5V, $\overline{OE}$=GND, CP=↓			33	48	mA
		I_{CCL}		$\overline{MR}$=$\overline{OE}$=D_n=D_s=GND, PE=4.5V, CP=↓			35	50	mA
		I_{CCZ}		$\overline{MR}$=D_n=D_s=GND, $\overline{OE}$=4.5V			32	46	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
2. All typical values are at V_{CC} = 5V, T_A = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

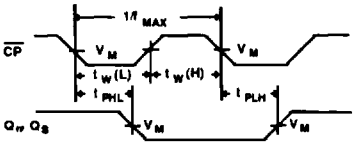
AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			T_A = +25°C, V_{CC} = 5V, C_L = 50pF, R_L = 500Ω			T_A = 0°C to +70°C, V_{CC} = 5V ±10%, C_L = 50pF, R_L = 500Ω		
			Min	Typ	Max	Min	Max	
f_{MAX}	Maximum clock frequency	Waveform 1	105	120		95		MHz
t_{PLH} t_{PHL}	Propagation delay $\overline{CP}$ to Q_n	Waveform 1	3.5 5.0	6.0 8.0	8.5 11.0	3.5 5.0	9.5 11.5	ns
t_{PLH} t_{PHL}	Propagation delay CP to Q_S	Waveform 1	5.0 5.5	6.5 7.5	9.0 10.0	4.5 5.0	10.0 10.5	ns
t_{PHL}	Propagation delay $\overline{MR}$ to Q_n	Waveform 2	5.0	7.5	10.0	5.0	10.5	ns
t_{PHL}	Propagation delay $\overline{MR}$ to Q_S	Waveform 2	4.5	7.0	9.0	4.5	9.5	ns
t_{PZH} t_{PZL}	Output Enable time to High or Low level	Waveform 4 Waveform 5	4.0 3.5	6.5 6.0	9.0 8.0	4.0 3.5	10.0 8.5	ns
t_{PHZ} t_{PLZ}	Output Disable time from High or Low level	Waveform 4 Waveform 5	1.0 1.0	2.5 3.5	4.5 5.5	1.0 1.0	5.5 6.5	ns

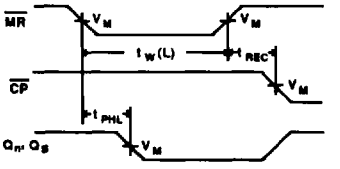
AC SETUP REQUIREMENTS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			T_A = +25°C, V_{CC} = 5V, C_L = 50pF, R_L = 500Ω			T_A = 0°C to +70°C, V_{CC} = 5V ±10%, C_L = 50pF, R_L = 500Ω		
			Min	Typ	Max	Min	Max	
$t_s(H)$ $t_s(L)$	Setup time, High or Low D_n to $\overline{CP}$	Waveform 3	2.5 1.5			3.0 2.0		ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low D_n to $\overline{CP}$	Waveform 3	1.5 1.5			1.5 1.5		ns
$t_s(H)$ $t_s(L)$	Setup time, High or Low PE to $\overline{CP}$	Waveform 3	6.5 6.0			7.0 6.5		ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low PE to $\overline{CP}$	Waveform 3	0 0			0 0		ns
$t_w(H)$ $t_w(L)$	$\overline{CP}$ Pulse width High or Low	Waveform 1	5.0 4.0			5.5 4.5		ns
$t_w(L)$	$\overline{MR}$ Pulse width Low	Waveform 2	2.5			3.0		ns
t_{REC}	Recovery time $\overline{MR}$ to $\overline{CP}$	Waveform 2	6.0			7.0		ns

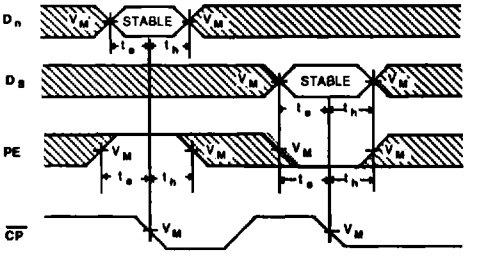
AC WAVEFORMS



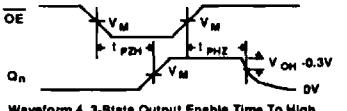
Waveform 1. Propagation Delay, Clock Input to Output, Clock Widths, and Maximum Clock Frequency



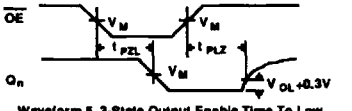
Waveform 2. Master Reset Pulse Width, Master Reset to Output Delay and Master Reset to Clock Recovery Time



Waveform 3. Parallel Enable and Data Setup Time and Hold Time



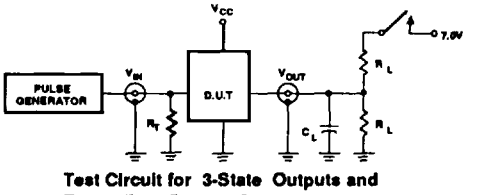
Waveform 4. 3-State Output Enable Time To High Level And Output Disable Time From High Level



Waveform 5. 3-State Output Enable Time To Low Level And Output Disable Time From Low Level

NOTE: For all waveforms, V_M = 1.5V.
The shaded areas indicate when the input is permitted to change for predictable output performance.

TEST CIRCUIT AND WAVEFORMS



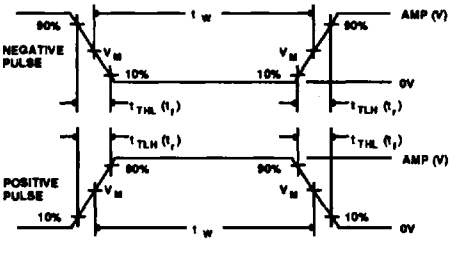
Test Circuit for 3-State Outputs and Totem-Pole Output (Q_S)

SWITCH POSITION

TEST	SWITCH
t_{PZL}, t_{PZL}	closed
All other	open

DEFINITIONS

R_L = Load resistor; see AC CHARACTERISTICS for value.
C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.
R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.



V_M = 1.5V

Input Pulse Definition

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_W	t_{TLH}	t_{THL}
74F	3.0V	1MHz	500ns	2.5ns	2.5ns